

CALL FOR PAPERS

Special Session: **Fault modeling and diagnosis.**

Organizators:

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Dear Colagues,

Motivated by the celebration of the 2015 IEEE International Autumn Meeting on Power, Electronics and Computing (XVII ROPEC, to be held in Ixtapa, Mexico, from 4 to November 6, 2015, with the website: [http://ropec.org /](http://ropec.org/)) we are organizing an invited session titled: Fault modeling and diagnosis.

The topics of interest in this session include all types of fault modeling as well fault diagnosis approaches. The idea is to show interesting aspects of modeling failures, as well as innovative applications of new or known techniques that allow motivated by the solution to troubleshoot problems. The idea is that various groups active in the area can show recent theoretical developments and applications of the different aspects of troubleshooting.

In order to better organize the invited session, we ask you to manifest interest in participating by sending an e-mail. Please, indicate the possible title of the contribution, the authors as well as the corresponding tentative assignment (as well as a summary of 300 words work). It is clear that the work will follow the normal process of review of the conference.

Important dates are:

From this moment. Manifestation of interest in the session: Modeling and fault diagnosis and sending the title, probable participants and secondment. (As well as a 300-word abstract of the work).

Email address: efrain.alcortagr@uanl.edu.mx

July 17, 2015 Paper submission deadline following the ROPEC 2015 guidelines.

September 4, 2015 Notification of acceptance.

September 18, 2015 Receipt of final papers and the conference early registration.

We would appreciate declared his decision (to participate or not in session) as soon as possible.

Sincerely,

Organizators.